
**Optics and photonics — Spectroscopic
measurement methods for integrated
scattering by plane parallel optical
elements**

*Optique et photonique — Méthodes de mesure spectroscopique pour
la diffusion intégrée par des éléments optiques à plans parallèles*



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ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
Email: copyright@iso.org
Website: www.iso.org

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see www.iso.org/iso/foreword.html.

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Introduction

Light scattering by optical components reduces the efficiency of optical systems and degrades the quality of image formation. Imperfections of the coatings and optical surfaces of the components predominantly produce light scattering. These imperfections involve surface and interface roughness; contamination; scratches; and defects of substrates, thin films and interfaces. Imperfections divert a fraction of the incident radiation from the optical path. The spatial distribution of this scattered radiation is dependent on the power spectral density function of the surface and interface's roughness, on the wavelength of the incident radiation and on the individual optical properties of the component. The wavelength dependence of the scattered radiation is indispensable information for characterizing optical components.

This document proposes a simple spectroscopic method for probing minute scattered radiation using a conventional double-beam spectrophotometer (hereafter, double-beam spectrophotometer) that is widely used for evaluating optical components.

Optics and photonics — Spectroscopic measurement methods for integrated scattering by plane parallel optical elements

1 Scope

This document specifies procedures for determining the spectroscopic forward scattering characteristics of coated and uncoated optical surfaces over a specified wavelength range between 350 nm and 850 nm using a double-beam spectrophotometer with an integrating sphere. This document is also applicable to the forward scattering properties at a single wavelength.

This document is applicable to spectroscopic forward scattering measurements with collection angles larger than 2,7 degrees. ISO 13696 provides a measurement method for smaller collection angles.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 291, *Plastics — Standard atmospheres for conditioning and testing*

3 Terms, definitions and symbols

3.1 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>

3.1.1

rear surface

surface that interacts last with the transmitted radiation

[SOURCE: ISO 13696:2002, 3.1.3]

3.1.2

forward scattered radiation

fraction of incident radiation scattered by an optical component into the forward half-space excluding that within a cone with a specified angle about the normal direction

Note 1 to entry: The forward half-space is defined by the half-space that contains the beam transmitted by the component that is limited by a plane containing the rear surface of the optical component.

3.1.3

forward scattering

ratio of the power of the forward scattered radiation to the power of the incident radiation